DOCUMENT CHANGE REQUEST

DCR number 688

Changes required for: N/A

Originator: Benoit Cornanguer

Date: 2011/12/06

Date sent: 2011/10/26

Organisation: STMicroelectronics

Status: IMPLEMENTED

Title:	TRANSISTORS, POWER, MOSFET, N-CHANNEL, RAD-HARD BASED ON TYPE STRH8N10		
Number:	5205/023	Issue:	1

Other documents affected:

Page:

Pages 10 & 11

Paragraph:

para: 2.5.1 Room Temperature Electrical Measurements

Original wording:

The limits of the AC test parameters [Qgs-Qgd-td(on)-trtd(off)-tf] need to be updated as defined below:
Qgs: minimum limit=3nC instead of 3.5nC
Qgd: minimum limit=4nC instead of 4.5nC
Qgd: maximum limit=7nC instead of 6.7nC
td(on): minimum limit=6ns instead of 6.5ns
td(on): maximum limit=15ns instead of 9.7ns
tr: maximum limit=17ns instead of 6ns
td(off): maximum limit=30ns instead of 20ns
tf: minimum limit=3ns instead of 4.5ns
tf: maximum limit=8ns instead of 6.8ns

Proposed wording:

Justification:

The ESCC detail specification has been written from the characterization results.
All AC electrical test parameters during the characterization phase have been done near of the body of the TO-39 package.
Unlike for the ESCC qualification we have used a test socket; in this case we lost performance for the switching times and gate charge due to that the measurements are done more far of the body of the package.
If we take into account this statement, we are sure to cover all customer applications by giving to them the worst limits.
(This is not the case if we keep the limits defined after the characterization).

Attachments:
N/A
Modifications:
N/A
Approval signature:
Date signed:
2011-12-06